

Dual P-Channel 12-V (D-S) MOSFET , ESD Protected

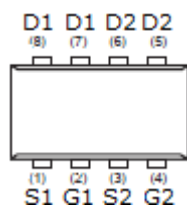
GENERAL DESCRIPTION

The ME5937ED is the Dual P-Channel logic enhancement mode power field effect transistors, using high cell density, DMOS trench technology. This high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage application such as cellular phone, notebook computer power management and other battery powered circuits, and lower power loss that are needed in a very small outline surface mount package.

PIN CONFIGURATION

(DFN 2x3 NEP)

Top View

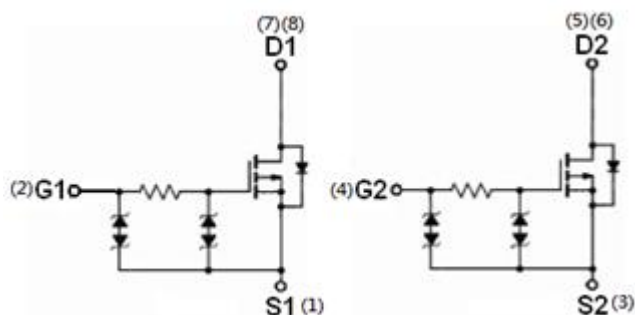


FEATURES

- $R_{DS(ON)} \leq 62m\Omega @ V_{GS} = -4.5V$
- $R_{DS(ON)} \leq 77m\Omega @ V_{GS} = -2.5V$
- $R_{DS(ON)} \leq 110m\Omega @ V_{GS} = -1.8V$
- $R_{DS(ON)} \leq 180m\Omega @ V_{GS} = -1.5V$
- Super high density cell design for extremely low $R_{DS(ON)}$
- Exceptional on-resistance and maximum DC current capability

APPLICATIONS

- Power Management in Note book
- Portable Equipment
- Battery Powered System
- DC/DC Converter
- Load Switch
- DSC



Ordering Information: ME5937ED (Pb-free)

ME5937ED-G (Green product-Halogen free)

Absolute Maximum Ratings ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

Parameter		Symbol	Maximum Ratings	Unit
Drain-Source Voltage		V_{DS}	-12	V
Gate-Source Voltage		V_{GS}	± 8	V
Continuous Drain Current*	$T_A = 25^\circ\text{C}$	I_D	-3.3	A
	$T_A = 70^\circ\text{C}$		-2.7	
Pulsed Drain Current		I_{DM}	-13.5	A
Maximum Power Dissipation*	$T_A = 25^\circ\text{C}$	P_D	1.1	W
	$T_A = 25^\circ\text{C}$		0.7	
Junction and Storage Temperature Range		T_J, T_{stg}	-55 to 150	$^\circ\text{C}$
Junction-to-Ambient Thermal Resistance*		$R_{\theta JA}$	110	$^\circ\text{C/W}$

*The device mounted on 1in2 FR4 board with 2 oz copper

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Electrical Characteristics (T_J =25°C Unless Otherwise Specified)

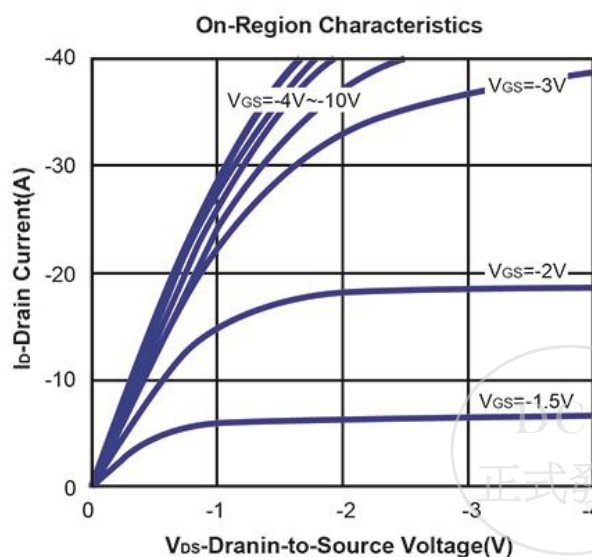
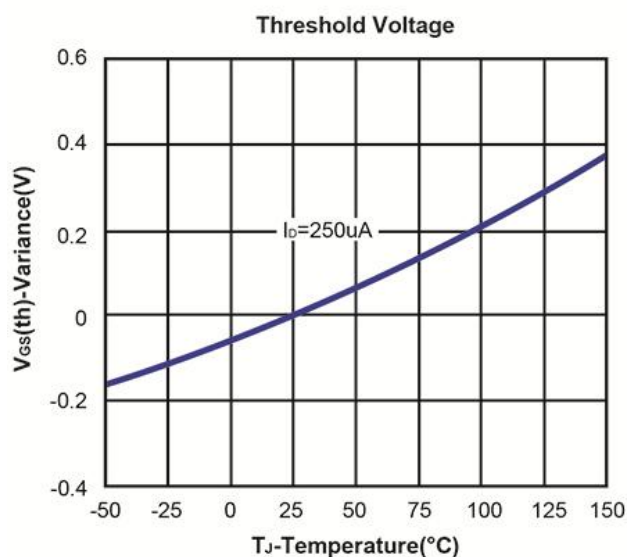
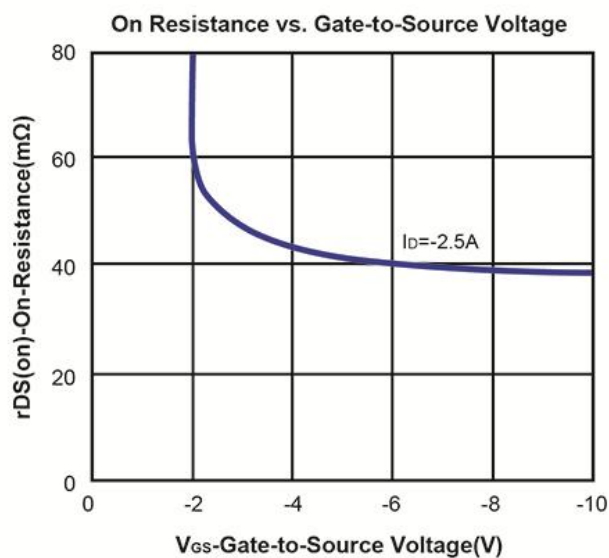
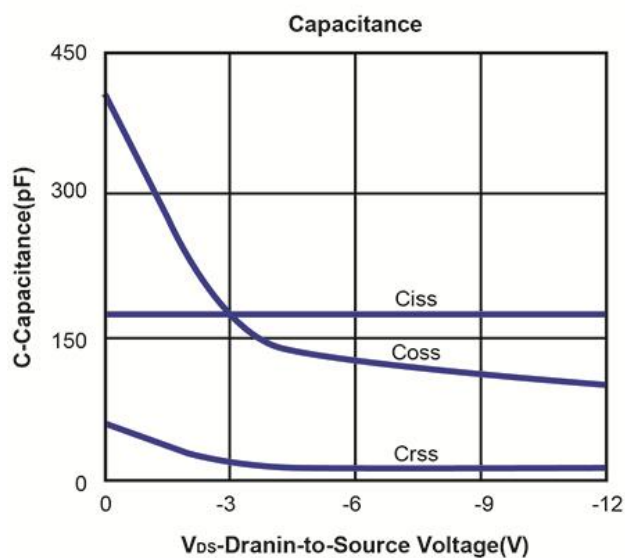
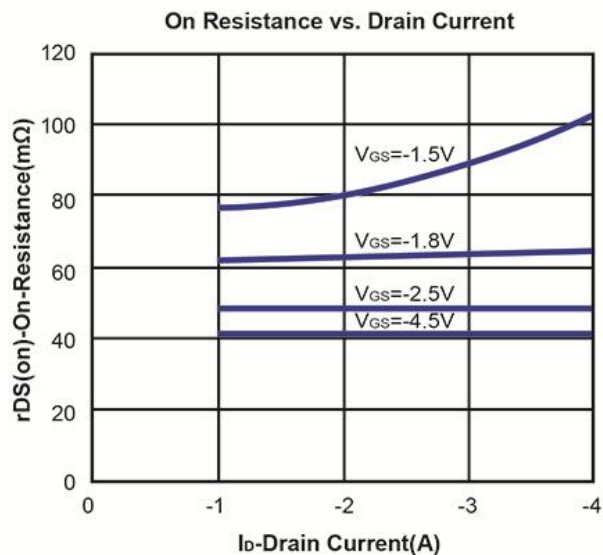
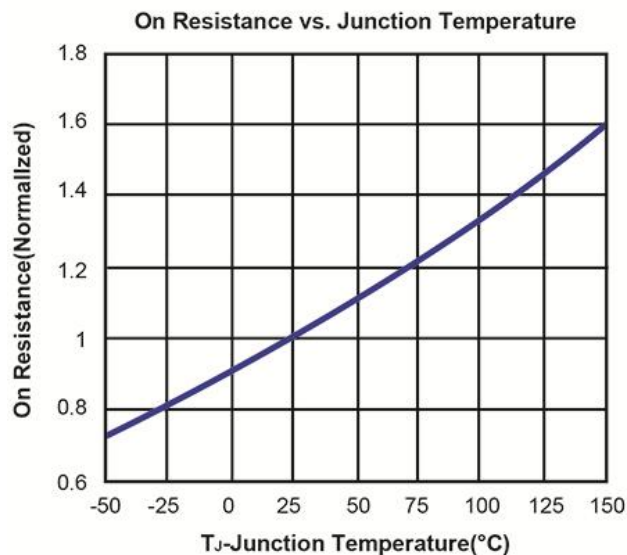
Symbol	Parameter	Limit	Min	Typ	Max	Unit
STATIC						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =-250uA	-12			V
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =-250uA	-0.3		-1.0	V
I _{GSS}	Gate Leakage Current	V _{DS} =0V, V _{GS} =±8V			±10	μA
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =-12V, V _{GS} =0V			-1	μA
R _{DS(ON)}	Drain-Source On-State Resistance ^a	V _{GS} =-4.5V, I _D = -2.5A		40	62	mΩ
		V _{GS} =-2.5V, I _D = -1.2A		48	77	
		V _{GS} =-1.8V, I _D = -1.2A		60	110	
		V _{GS} =-1.5V, I _D = -0.5A		78	180	
V _{SD}	Diode Forward Voltage	I _S =-2.5A, V _{GS} =0V,			-1.2	V
DYNAMIC						
C _{iss}	Input capacitance	V _{DS} =-6V, V _{GS} =0V, f=1.0MHz		170		pF
C _{oss}	Output Capacitance			122		
C _{rss}	Reverse Transfer Capacitance			14		
Q _g	Total Gate Charge	V _{DS} =-6V, V _{GS} =-4.5V, I _D =-2.5A		13		nC
Q _{gs}	Gate-Source Charge			1.1		
Q _{gd}	Gate-Drain Charge			2.4		
t _{d(on)}	Turn-On Delay Time	V _{DS} =-10V, R _L =2.5Ω R _{GEN} =3Ω, V _{GS} =-4.5V		560		ns
t _r	Turn-On Rise Time			4000		
t _{d(off)}	Turn-Off Delay Time			400		
t _f	Turn-Off Fall Time			4000		

Notes: a. Pulse test; pulse width ≤ 300us, duty cycle ≤ 2%

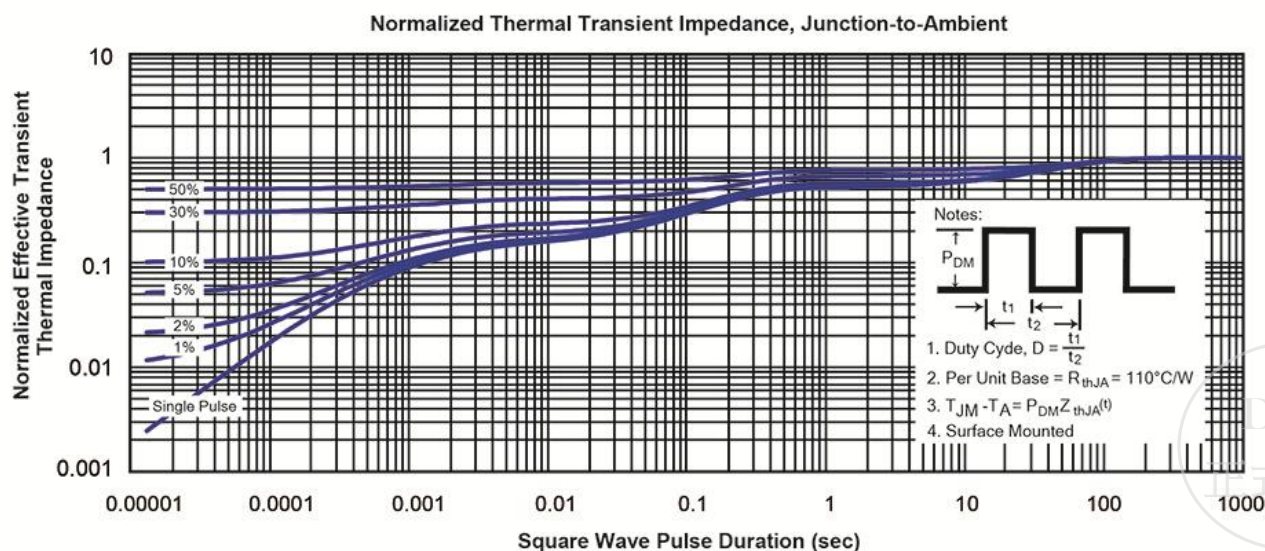
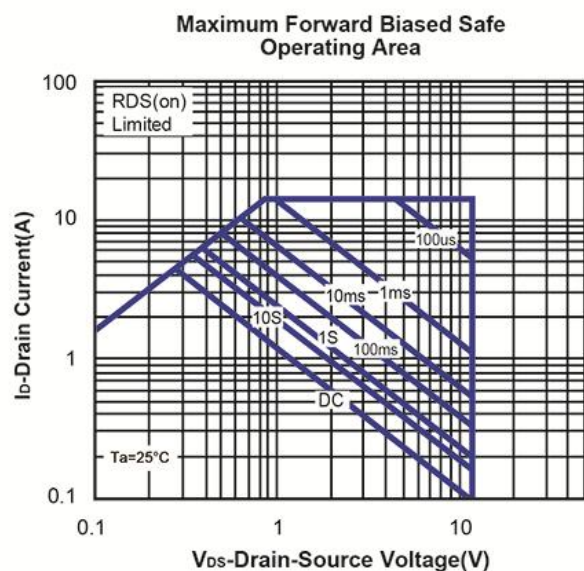
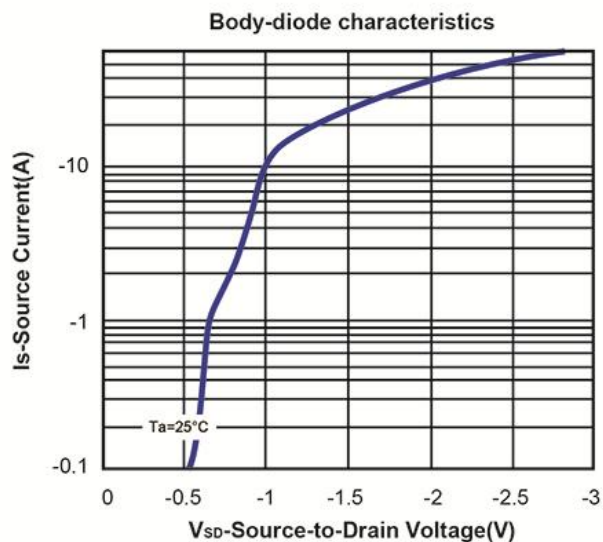
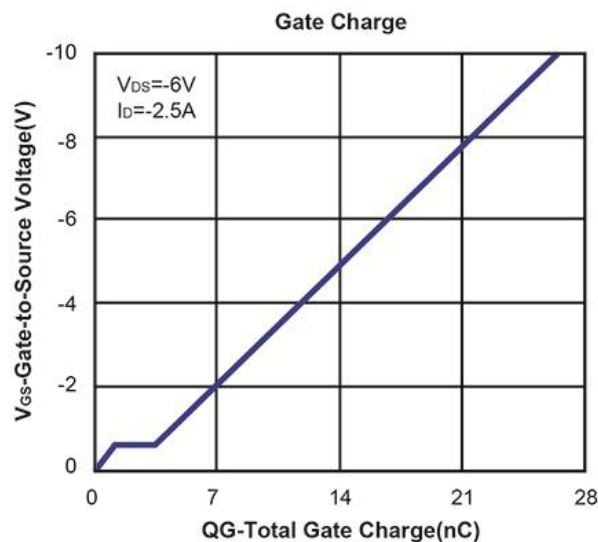
b. Matsuki Electric/ Force mos reserves the right to improve product design, functions and reliability without notice.

DCC
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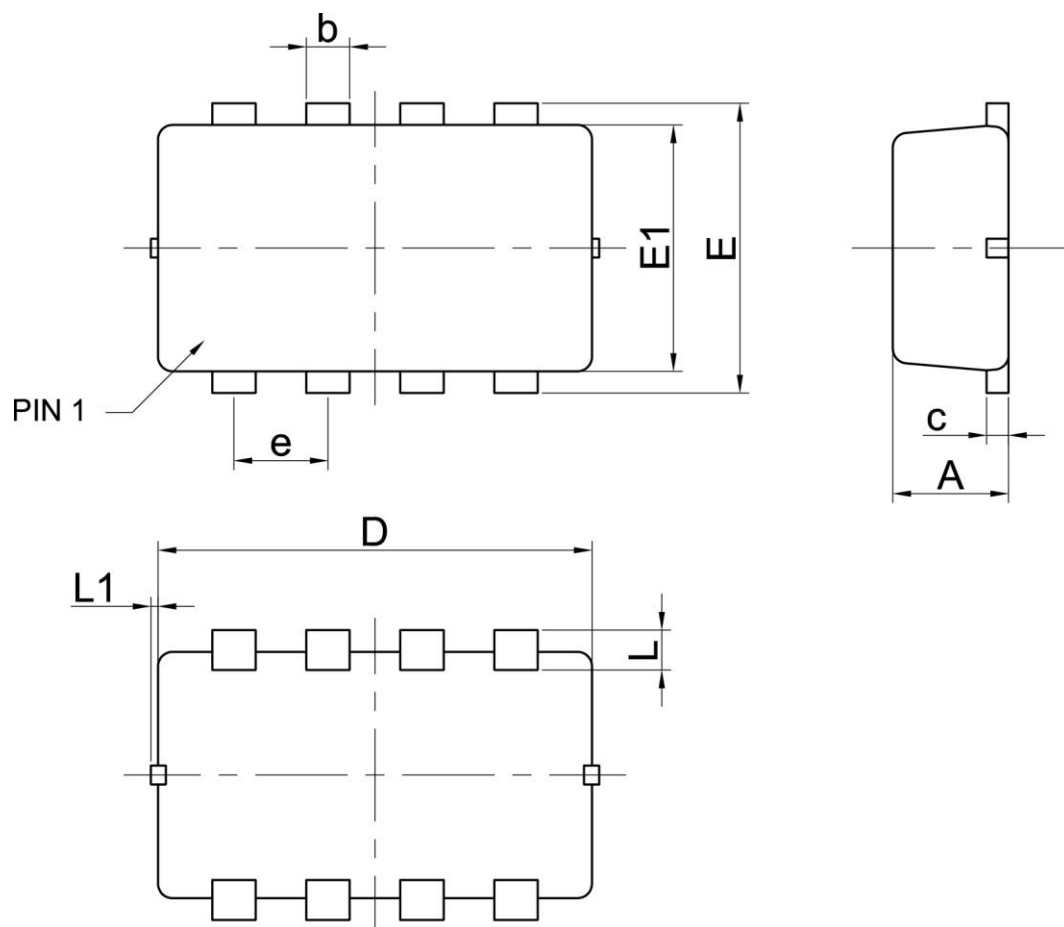
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Typical Characteristics (T_J =25°C Noted)



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DFN 3x2 NEP Package Outline



SYMBOL	MILLIMETERS (mm)	
	MIN	MAX
A	0.70	0.90
b	0.24	0.35
c	0.08	0.20
D	2.90	3.10
E	1.90	2.10
E1	1.60	1.75
e	0.65 BCS	
L	0.20	0.45
L1	0	0.10

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